## **LIST OF CLAIMS**

This listing of claims will replace all prior versions, and listings, of claims in the application.

- 1. (Currently amended) A chemical mechanical planarization (CMP) system, the system comprising:
  - a polishing surface;
  - a platen disposed along an underside of the polishing surface; and
- a retaining ring surrounding the platen, the retaining ring including a fixed lower annular sleeve.
- 2. (Currently amended) The CMP system of claim 1, wherein the retaining ring includes a lower annular sleeve and an upper annular sleeve moveably disposed over the lower annular sleeve.
- 3. (Original) The CMP system of claim 1, wherein the polishing surface is a belt.
- 4. (Original) The CMP system of claim 2, wherein the lower annular sleeve includes at least two lower curved members and the upper annular sleeve includes at least two upper curved members, each of the at least two upper curved members being moveably disposed over a corresponding lower curved member.
- 5. (Original) The CMP system of claim 2, wherein the lower annular sleeve includes a base having an inner sidewall and an outer sidewall extending

Docket No: LAM2P311A 3 Amendment

therefrom and the upper annular sleeve includes a top having an inner sidewall and an

outer sidewall extending therefrom.

6. (Original) The CMP system of claim 5, wherein an interior surface of

each of the inner and outer sidewalls of the upper annular sleeve includes a protrusion,

and an exterior surface of each of the inner and outer sidewalls of the lower annular

sleeve includes a protrusion.

7. (Original) The CMP system of claim 6, wherein the protrusions of the

upper and lower annular sleeves are positioned such that when the protrusion of the

upper annular sleeve abuts against the protrusion of the lower annular sleeve, the top

of the upper annular sleeve aligns to the underside of the polishing surface without

disturbing an interaction angle between a wafer and the polishing surface.

8. (Currently amended) The CMP system of claim 1, wherein a top

surface of the an upper annular sleeve has a channel formed therein.

9. (Currently amended) The CMP system of claim 1, wherein a top

surface of the an upper annular sleeve of the retaining ring has at least one hole

defined therein.

Claims 11-16 Cancelled

4 Docket No: LAM2P311A Amendment